S	earch	Notes	

Application/Control No.	Applicant(s)/Patent und Reexamination	ier
10/711,717	YAMASAKI ET AL.	
Examiner	Art Unit	
B. Chen	1762	

	SEARCHED		
Class	Subclass	Date	Examiner
updated	previous	3/19/2006	вс
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INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
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